

**Notice of References Cited**

Application/Control No.

09/458,796

Applicant(s)/Patent Under  
Reexamination  
GORDON ET AL.

Examiner

Son P Huynh

Art Unit

2611

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	U	Kawamura et al. (US 2001/0005447), June 28, 2001
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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